



BYD Microelectronics Co., Ltd.

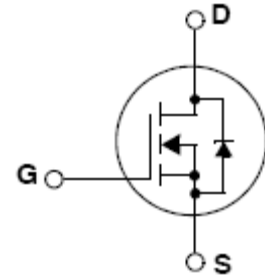
BF94N60/BF94N60L

600V N-Channel MOSFET

General Description

The N-Channel enhancement mode power field effect transistor is produced using DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switched mode power supplies, active power factor correction, electronic lamp ballasts based on half bridge topology.



Features

- $V_{DS} = 600\text{ V}$
- $I_D = 4\text{ A}$
- $R_{DS(ON)} = 1.9\ \Omega$ TYP ($V_{GS} = 10\text{ V}$, $I_D = 2\text{ A}$)
- Low C_{RSS} (typical 7.0pF)
- Fast switching



Absolute Maximum Ratings

| Symbol | Parameter | BF94N60L | BF94N60 | Unit |
|-----------|--|-------------|---------|------------------|
| V_{DS} | Drain-Source Voltage | 600 | | V |
| I_D | Drain Current(continuous)at $T_c=25^\circ\text{C}$ | 4 | | A |
| I_{DM} | Drain Current (pulsed) (Note1) | 16 | | A |
| V_{GS} | Gate-Source Voltage | ± 30 | | V |
| E_{AS} | SinglePulseAvalanche Energy (Note2) | 170 | | mJ |
| I_{AR} | Avalanche Current (Note1) | 4 | | A |
| E_{AR} | RepetitiveAvalancheEnergy (Note1) | 10 | | mJ |
| dv/dt | PeakDiodeRecovery dv/dt (Note3) | 5 | | V/ns |
| P_D | Power Dissipation ($T_c = 25^\circ\text{C}$) | 62 | 37 | W |
| T_{stg} | Storage Temperature Range | -55 to +150 | | $^\circ\text{C}$ |
| T_L | Maximum Lead Temperature for Soldering Purpose | 300 | | $^\circ\text{C}$ |



Ordering Information

| Part Number | Package | Packaging |
|-------------|---------|-----------|
| BF94N60 | TO-220F | Tube |
| BF94N60L | TO-220 | Tube |

Thermal Data

| Symbol | Parameter | TO-220F | TO-220 | Unit |
|-----------|-------------------------------------|---------|--------|-------|
| Rthj-case | Thermal Resistance Junction-case | 3.3 | 2.0 | °C /W |
| Rthj-amb | Thermal Resistance Junction-ambient | 62.5 | 62.5 | °C /W |

Electrical Characteristics(T_c = 25°C)

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Unit |
|----------------------|-----------------------------------|--|------|------|------|------|
| V _{(BR)DSS} | Drain-Source Breakdown Voltage | I _D =250uA, V _{GS} =0 | 600 | | | V |
| I _{DSS} | Zero Gate Voltage Drain Current | V _{DS} =600V, V _{GS} =0V | | | 1 | uA |
| | | V _{DS} =600V, V _{GS} =0V, T _c =125°C | | | 10 | uA |
| I _{GSS} | Gate-Body Leakage Current | V _{GS} =±30V, V _{DS} =0V | | | ±100 | nA |
| V _{GS(th)} | Gate Threshold Voltage | V _{DS} =V _{GS} , I _D =250uA | 2.0 | | 4.0 | V |
| R _{DS(on)} | Static Drain-Source On Resistance | V _{GS} =10V, I _D =2A | | 1.9 | 2.2 | Ω |
| C _{iss} | Input Capacitance | V _{DS} =25V, f=1MHZ, V _{GS} =0V | | 550 | | pF |
| C _{oss} | Output Capacitance | | | 60 | | pF |
| C _{rss} | Reverse Transfer Capacitance | | | 7.0 | | pF |
| t _{d(on)} | Turn-On Delay Time | V _{DD} =300V, I _D =2A V _{GS} =10V, R _G =4.7Ω (Note4, 5) | | 20 | | ns |
| t _r | Rise Time | | | 17 | | ns |
| t _{d(off)} | Turn-Off Delay Time | | | 47 | | ns |
| t _f | Fall Time | | | 18 | | ns |
| Q _g | Total Gate Charge | V _{DD} =480V, I _D =4A V _{GS} =10V (Note4, 5) | | 20 | | nC |
| Q _{gs} | Gate-Source Charge | | | 5.0 | | nC |
| Q _{gd} | Gate-Drain Charge | | | 5.7 | | nC |
| V _{SD} (*) | Forward On Voltage | I _F =4A, V _{GS} =0V | | 0.8 | 1.2 | V |
| T _{rr} | Reverse Recovery Time | V _{DD} =300V, I _F =4A, di/dt=100A/us (Note4) | | 280 | | ns |

Notes:

1. Repetitive Rating : Pulse width limited by maximum junction temperature
 2. L = 20mH, I_{AS} = 4A, V_{DD} = 50V, R_G = 25 Ω, Starting T_J = 25°C
 3. I_{SD} ≤ 4 A, di/dt ≤ 200A/μs, V_{DD} ≤ BV_{DSS}, Starting T_J = 25°C
 4. Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2%
 5. Essentially independent of operating temperature
- (*).Pulsed:Pulse duration



Typical characteristics (25°C unless noted)

Figure 1 Output Characteristics

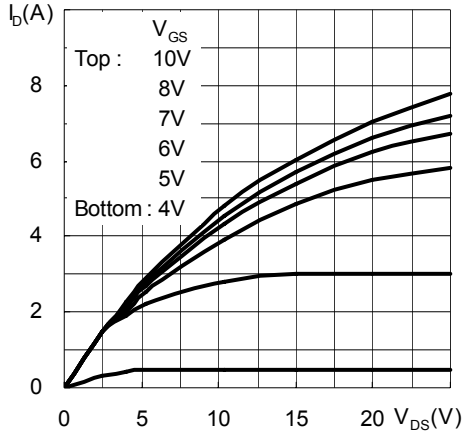


Figure 2 Transfer Characteristics

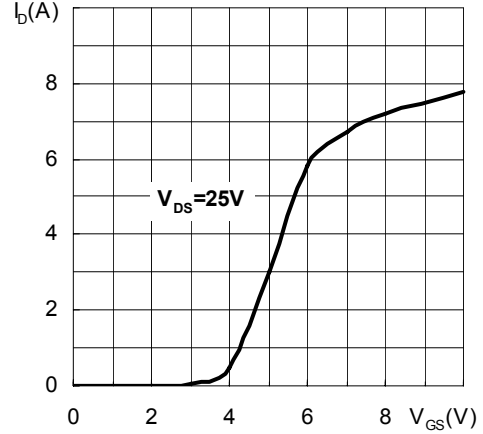


Figure 3 Normalized Threshold Voltage vs. Temperature

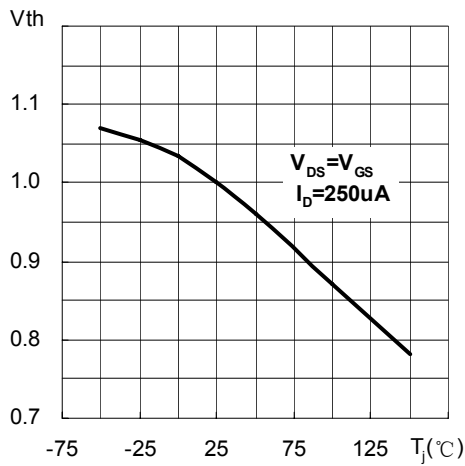


Figure 4 Normalized BV_{DSS} vs. Temperature

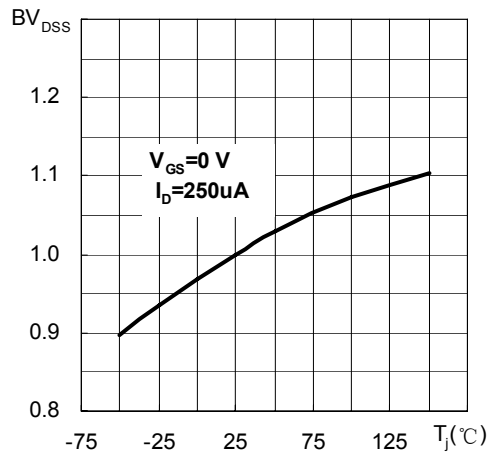


Figure 5 Normalized on Resistance vs Temperature

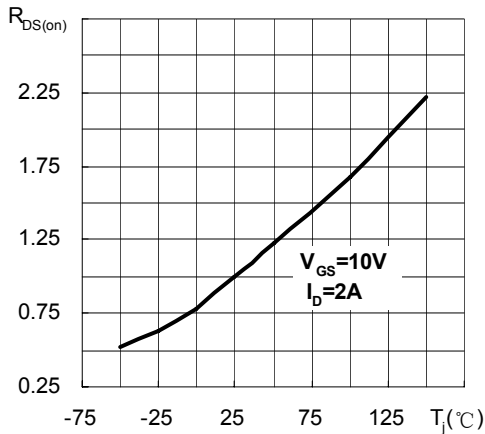


Figure 6 Source-Drain Diode Forward Characteristics

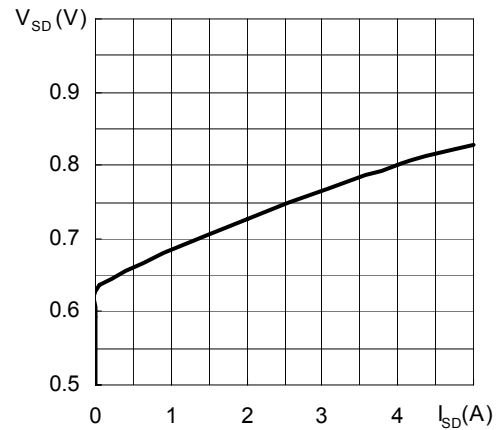




Figure 7 Capacitance

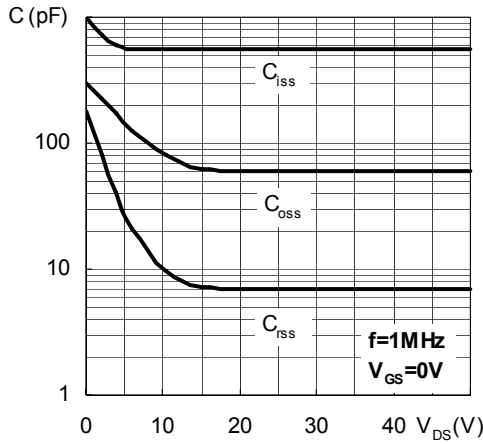


Figure 8 Gate Charge

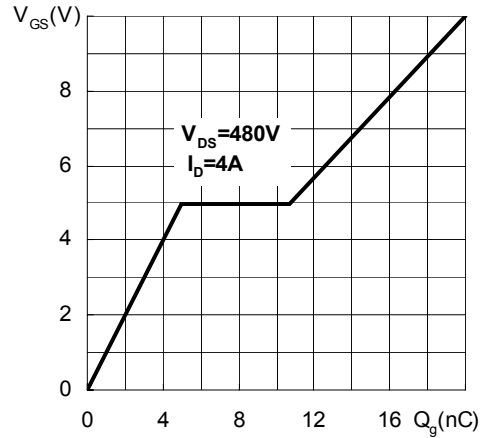


Figure 9-1 Safe Operating Area For BF94N60

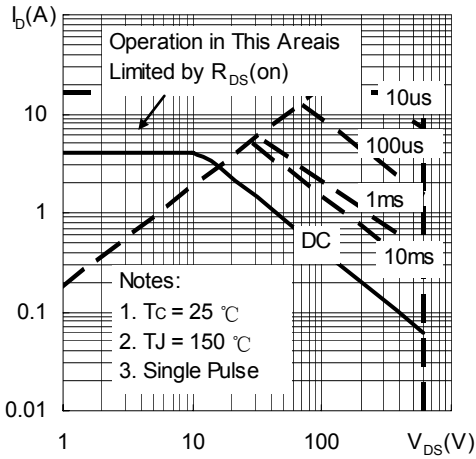


Figure 9-2 Maximum Safe Operating Area For BF94N60L

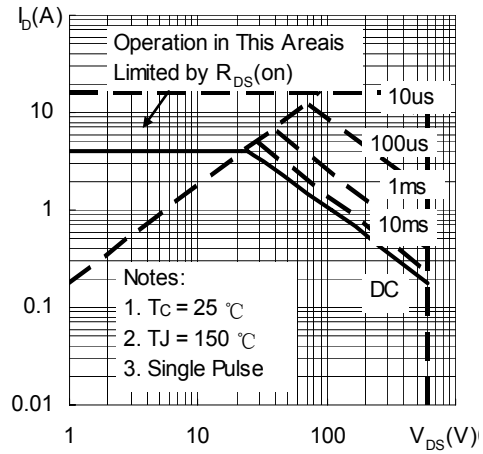


Figure 10 Maximum Drain Current vs Case Temperature

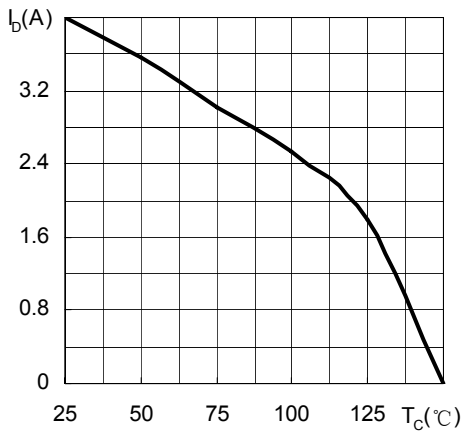


Figure 11-1 Maximum Transient Thermal Impedance For BF94N60

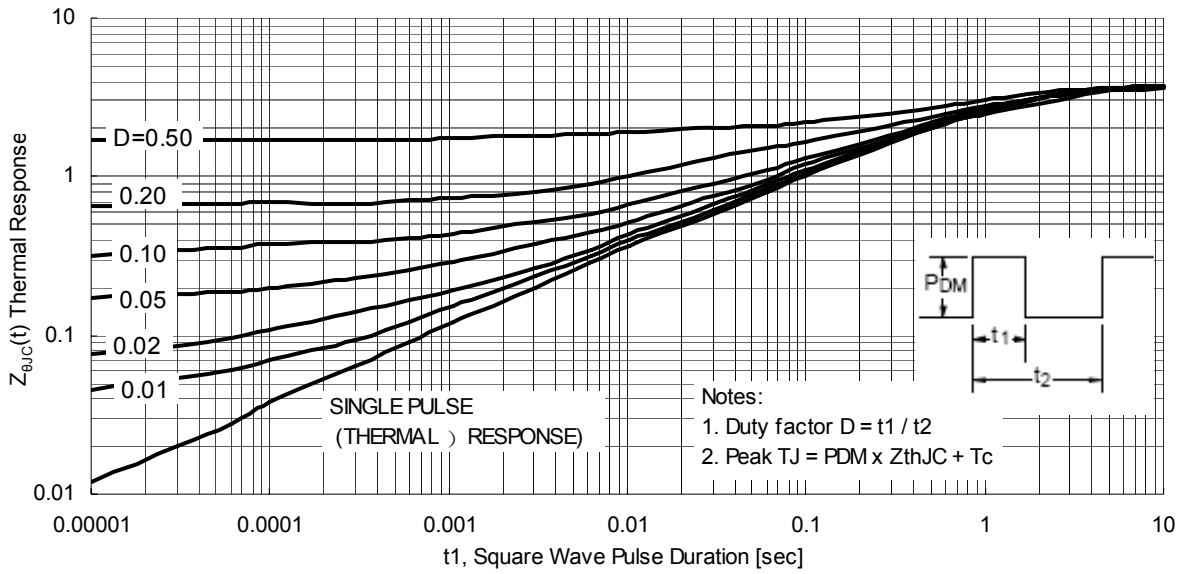
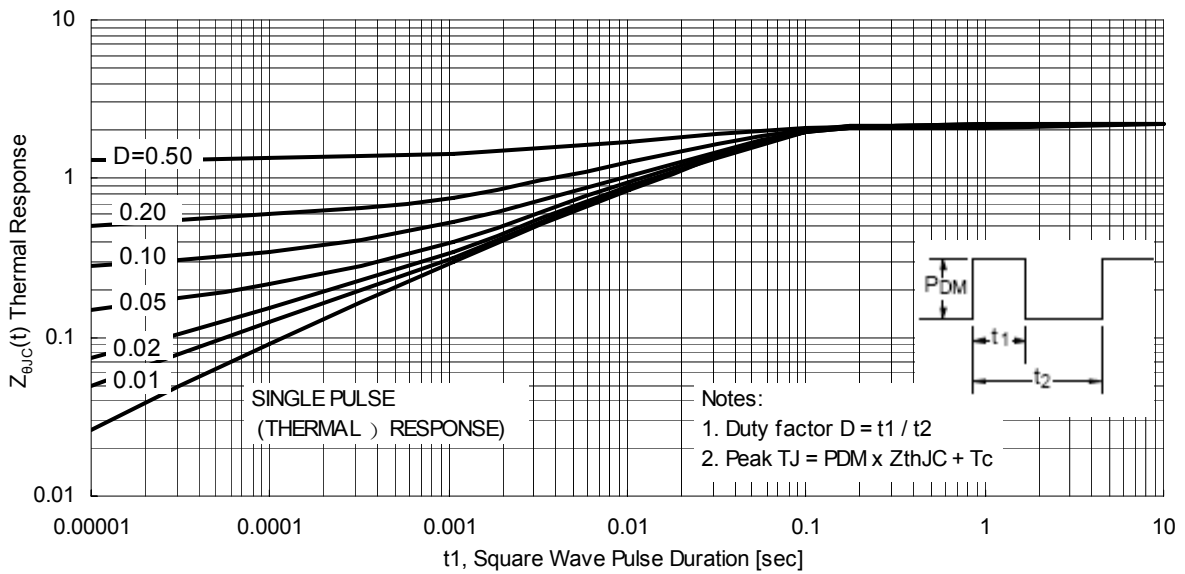
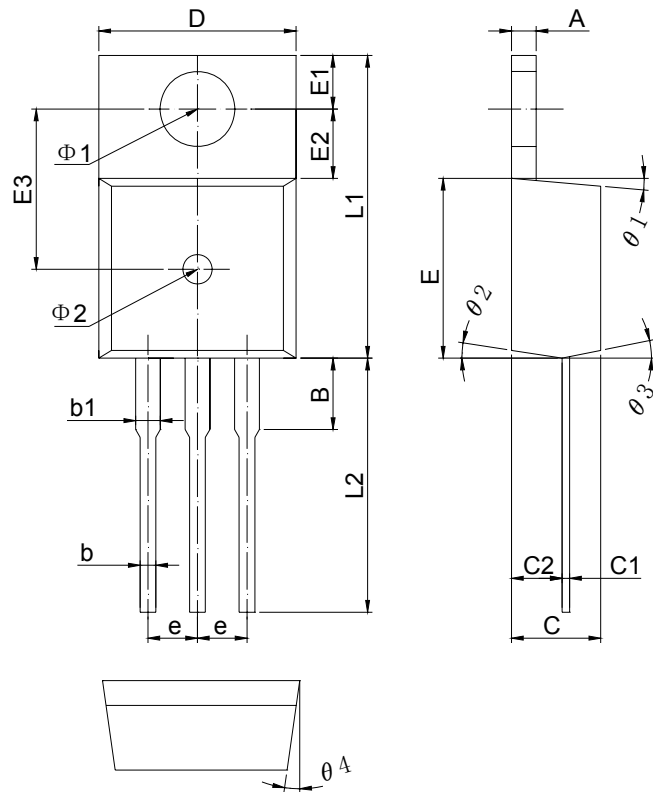


Figure 11-2 Maximum Transient Thermal Impedance For BF94N60L



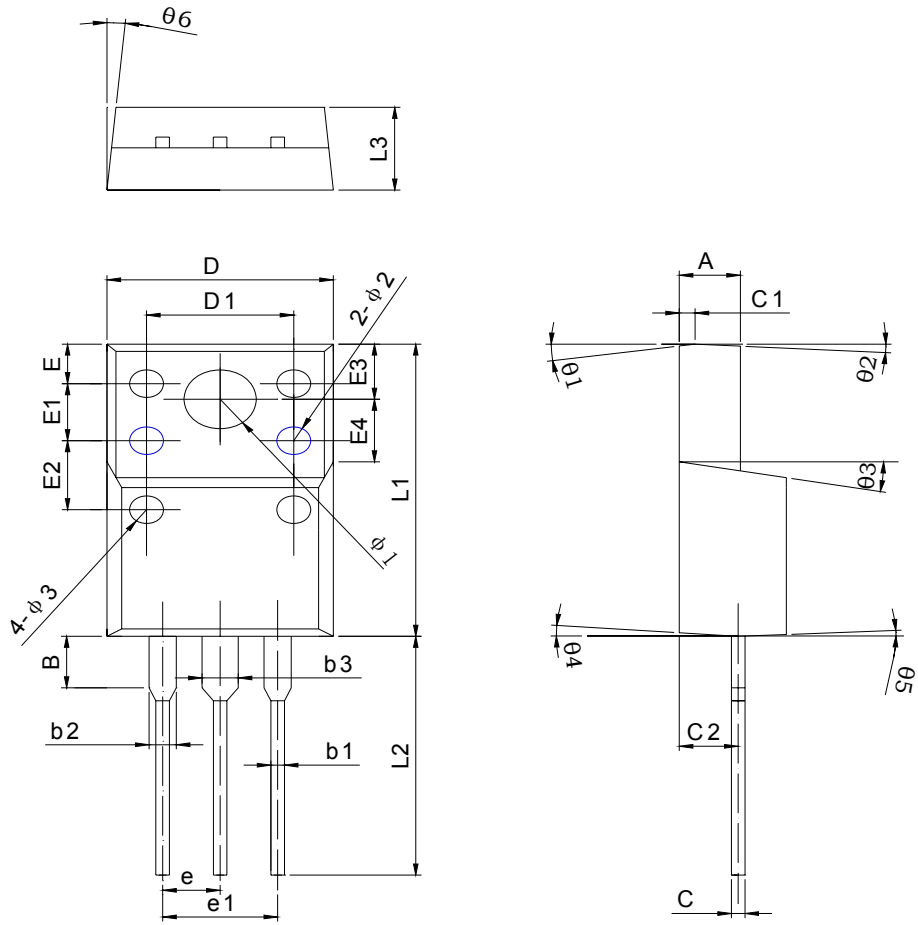
Package Drawing
TO-220



| Symbol | Dimensions In Millimeters | | | Dimensions In Inches | | |
|------------|---------------------------|-------|-------|----------------------|-------|-------|
| | Min | Nom | Max | Min | Nom | Max |
| A | - | 1.27 | - | - | 0.050 | - |
| B | - | 3.65 | - | - | 0.144 | - |
| b | - | 0.81 | - | - | 0.032 | - |
| b1 | - | 1.27 | - | - | 0.050 | - |
| C | - | 4.58 | - | - | 0.180 | - |
| C1 | - | 0.38 | - | - | 0.015 | - |
| C2 | - | 2.60 | - | - | 0.102 | - |
| D | 10.10 | 10.12 | 10.14 | 0.398 | 0.398 | 0.399 |
| E | - | 9.20 | - | - | 0.362 | - |
| E1 | - | 2.74 | - | - | 0.108 | - |
| E2 | - | 3.55 | - | - | 0.140 | - |
| E3 | - | 8.20 | - | - | 0.323 | - |
| e | 2.515 | 2.54 | 2.565 | 0.099 | 0.100 | 0.101 |
| L1 | 15.47 | 15.49 | 15.51 | 0.609 | 0.610 | 0.611 |
| L2 | 13.00 | - | - | 0.512 | - | - |
| $\theta 1$ | 3° | | | 3° | | |
| $\theta 2$ | 3° | | | 3° | | |
| $\theta 3$ | 3° | | | 3° | | |
| $\theta 4$ | 3° | | | 3° | | |
| $\phi 1$ | 3.84 | | | 0.151 | | |
| $\phi 2$ | 1.5 | | | 0.059 | | |



TO-220F





| Symbol | Dimensions In Millimeters | | | Dimensions In Inches | | |
|--------|---------------------------|-------|-------|----------------------|-------|-------|
| | Min | Nom | Max | Min | Nom | Max |
| A | 2.50 | 2.70 | 2.90 | 0.098 | 0.106 | 0.114 |
| B | 2.60 | 2.80 | 3.00 | 0.102 | 0.110 | 0.118 |
| b1 | 0.50 | 0.60 | 0.70 | 0.020 | 0.024 | 0.028 |
| b2 | 1.10 | 1.20 | 1.30 | 0.043 | 0.047 | 0.051 |
| b3 | - | 1.60 | - | - | 0.063 | - |
| C | 0.55 | 0.60 | 0.65 | 0.022 | 0.024 | 0.026 |
| C1 | - | 0.60 | - | - | 0.024 | - |
| C2 | 2.40 | 2.60 | 2.80 | 0.094 | 0.102 | 0.110 |
| D | 9.80 | 10.00 | 10.20 | 0.386 | 0.394 | 0.402 |
| D1 | - | 6.50 | - | - | 0.256 | - |
| E | - | 2.15 | - | - | 0.085 | - |
| E1 | - | 3.10 | - | - | 0.122 | - |
| E2 | - | 3.75 | - | - | 0.148 | - |
| E3 | 2.90 | 3.00 | 3.10 | 0.114 | 0.118 | 0.122 |
| E4 | 3.30 | 3.40 | 3.50 | 0.130 | 0.134 | 0.138 |
| e | - | 2.54 | - | - | 0.100 | - |
| e1 | 4.98 | 5.08 | 5.18 | 0.196 | 0.200 | 0.204 |
| L1 | 14.80 | 15.00 | 15.20 | 0.583 | 0.591 | 0.598 |
| L2 | 13.00 | 13.20 | 13.40 | 0.512 | 0.520 | 0.528 |
| L3 | 4.30 | 4.50 | 4.70 | 0.169 | 0.177 | 0.185 |
| θ1 | 5° | | | 5° | | |
| θ2 | 3° | | | 3° | | |
| θ3 | 10° | | | 10° | | |
| θ4 | 5° | | | 5° | | |
| θ5 | 3° | | | 3° | | |
| θ6 | 5° | | | 5° | | |
| φ1 | 3.00 | 3.20 | 3.40 | 0.118 | 0.126 | 0.134 |
| φ2 | 1.50 深 1.2 头部 160° | | | 1.50 深 1.2 头部 160° | | |
| φ3 | 1.50 深 0.1 | | | 1.50 深 0.1 | | |



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